

ISSUE CLASSIFICATION	
Class	Subclass

PATENT NUMBER

U.S. **UTILITY** Patent Application

<p>O.I.P.E.</p> <p>AC <u>203</u> Q.A. <u>WOB</u></p> <p>SCANNED</p>	<p>PATENT DATE</p>
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APPLICATION NO. 097659211	CONT/PRIOR F	CLASS 438	SUBCLASS 680	ART UNIT 2812 2825	EXAMINER Everhart
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TITLE

Noriyuki Hirayanagi

Alignment-mark detection methods and devices for charged-particle-beam microlithography, and microelectronic-device manufacturing methods comprising same

PTO-2040
12/89

ISSUING CLASSIFICATION												
ORIGINAL				CROSS REFERENCE(S)								
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
INTERNATIONAL CLASSIFICATION												

☐ Continued on Issue Slip Inside File Jacket

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.			NOTICE OF ALLOWANCE MAILED	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____				
			ISSUE FEE	
			Amount Due	Date Paid
<input type="checkbox"/> The terminal ____ months of this patent have been disclaimed.			ISSUE BATCH NUMBER	
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